

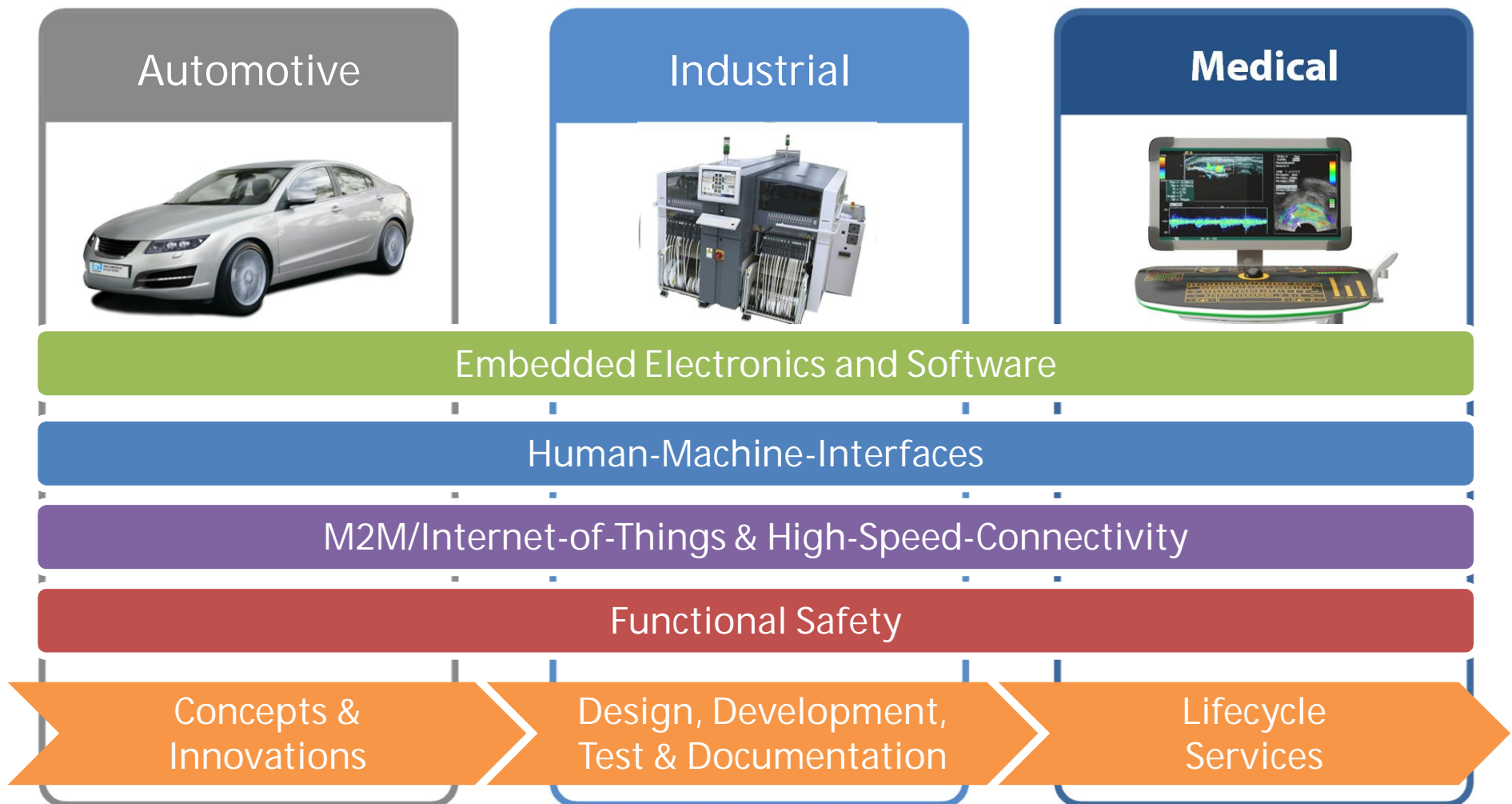


# EMC Test Adapter for MTCA.4 Modules

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# b1 Engineering Solutions: Markets and Solutions



# The MTCA.4 EMC Challenge

All boards within a crate influence each other:

- *All boards are coupled via GND*



- *Near field/far field interference between neighbouring boards*
- *Boards from different manufacturers*
- *Noise from neighboring boards may limit performance*

# Modelling and Classification of MTCA.4 Boards

- *Modelling of the GND system by means of equivalent circuits.  
See: GND Modelling of MTCA.4 Crates (3rd MTCA Workshop)*
- *Definition of sensitivity classes giving limits on emission and immunity for all coupling paths.*
  - *Evaluate the model parameters, e.g. the impedances of the equivalent circuits*
  - *Quantify the susceptibility of components (signals, power supply, ..)*
  - *Calculate the effectiveness of shielding/filtering/distance on noise attenuation*
  - *Define the allowed noise levels*
- *In-System Classification of AMC-Modules*
  - *system dependent*
  - *portability to other systems?*

# Stand Alone Classification of AMC-Modules

## Conductive Coupling

### ● *Emission*

- *Measurement Setup:*  
*stand alone characterization of active components: AMC*  
*frequency domain: spectral density (e.g. 10Hz – 100MHz)*  
*time domain: voltage / current*
- *Measurement Parameter:*  
*noise voltage/current payload voltage and on GND*  
*(each referenced to measurement GND)*
- *Limits: integral, set of curves - values: t.b.d.*

### ● *Susceptibility*

- *Measurement Setup:*  
*well defined interfering signal applied to AMC*  
*continuous signal, transient signal*
- *Measurement Parameter:*  
*full functionality of AMC (to be defined in specification of module under test)*
- *Limits*  
*amplitude of continuous wave signal at certain frequencies*  
*amplitude and duration of transient signal*

## Radiation

- *still open*

# EMC Adapter Board Concept

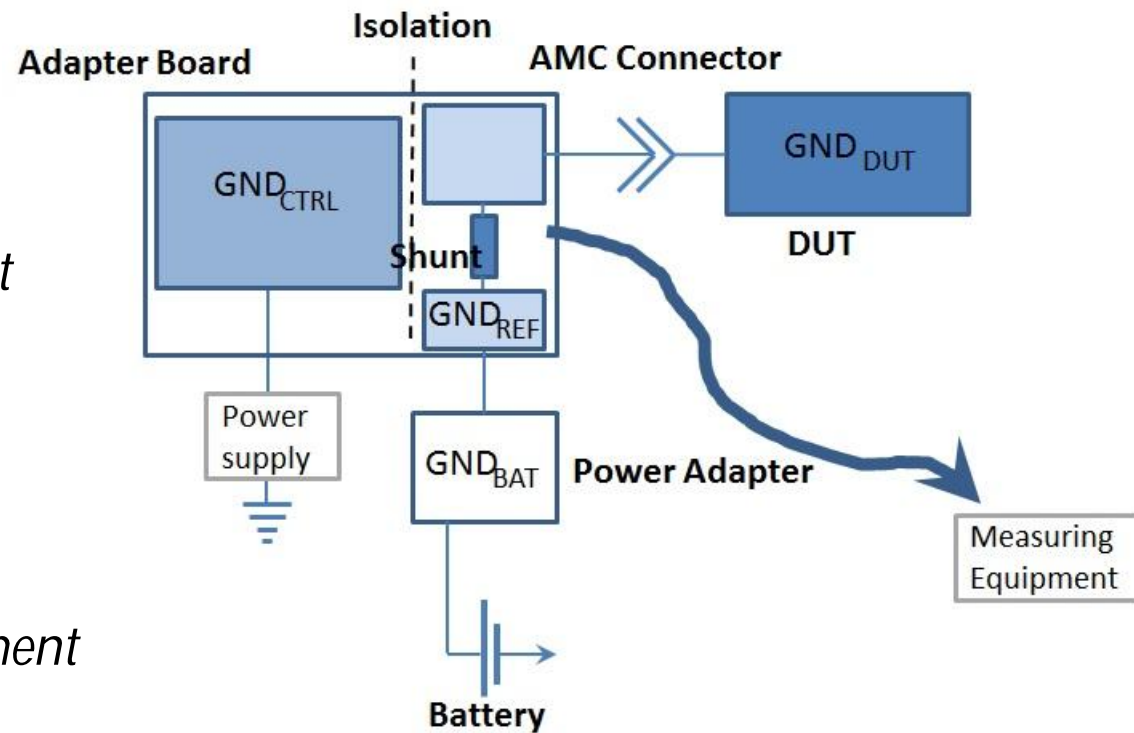
Provide the possibility to evaluate the EMI behavior of AMC modules by spectral or time domain measurements of ground noise currents and voltages

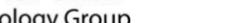
- *Standardized AMC connector for AMC card plug-in*
- *Management and payload power supply*
- *Power management*
- *Clock generation*
- *Selected fat pipe connections*
- *Basic IPMI functionality (hot-swap, temperature surveillance, ...)*
- *stand-alone operation*  
*or*  
*within a MTCA crate replacing the backplane, power module and MCH*  
*→ form factor of MTCA backplane*

# EMC Adapter Board Measurement Principle

- *Measurement of GND current via a shunt resistor*
- *Grounding concept*

- *Battery supply avoid earth loops & noise from external equipment*
- *Galvanic isolation of control & measurement*
- *measurements may use the ground of the measuring equipment*





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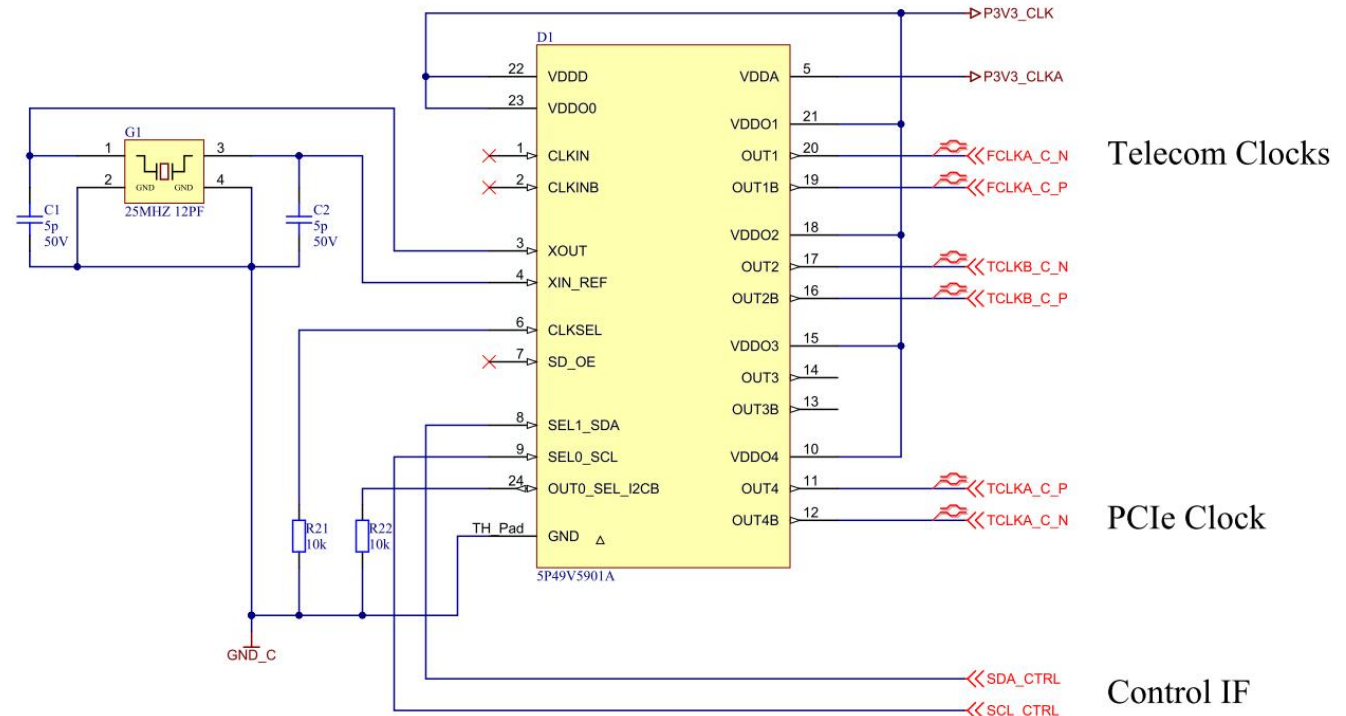


# Controller HW Functions

- *Processor ATXMEGA128A1-A*
- *Provide I<sup>2</sup>C interface for IPMB-L (communication with AMC board) selectable via processor subsystem and connector via jumper.*
- *Detect present signal PS1#*
- *Generate ON signal to Power Adapter*
- *Generate ENABLE# signal to AMC*
- *Temperature surveillance of the AMC module which indicates critical temperature and shutdown the AMC if the temperature exceeds the tolerable limit.*
- *Provide programmable backplane clocks*
- *Provide Control&Interlock Signals*

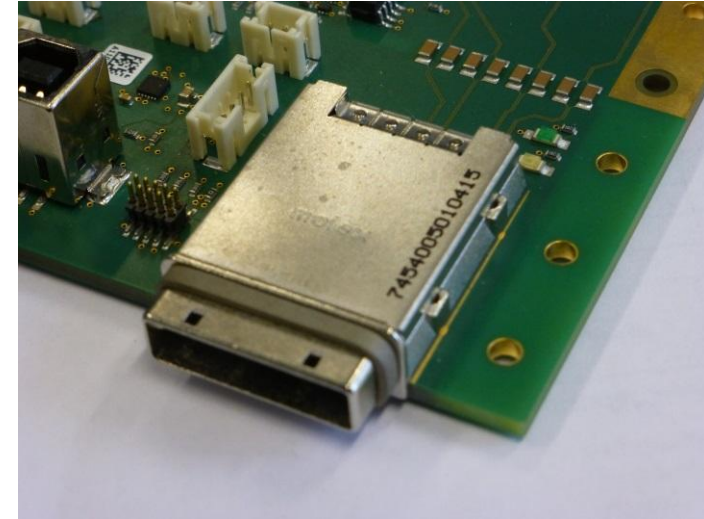
# Clock Generator

- *Programmable Clock Generator*
- *I<sup>2</sup>C serial programming interface*
- *Differential Outputs*
- *LVDS*
- *1MHz to 350MHz*



# PCIe Connection

- *external PCIe x4 Interface*
- *AMC Port 4 to 7*
- *Standard PCIe connector*
- *Signals have to be provided from PC*
- *Galvanic Isolation possible using optical interface e.g. SAMTEC*



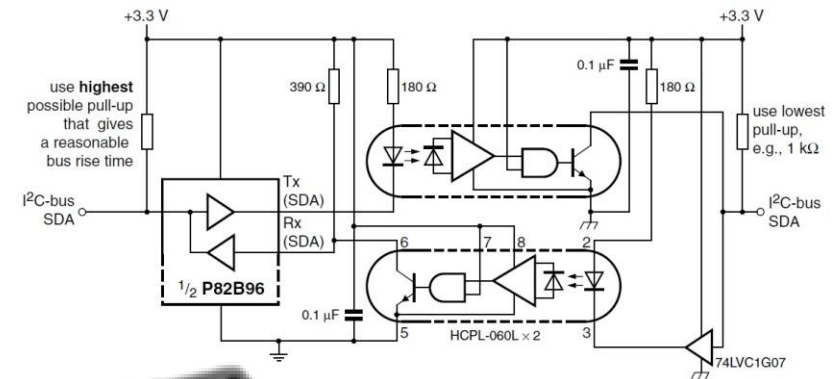
**samtec**

PCIe® Active Optical  
Cable Assemblies

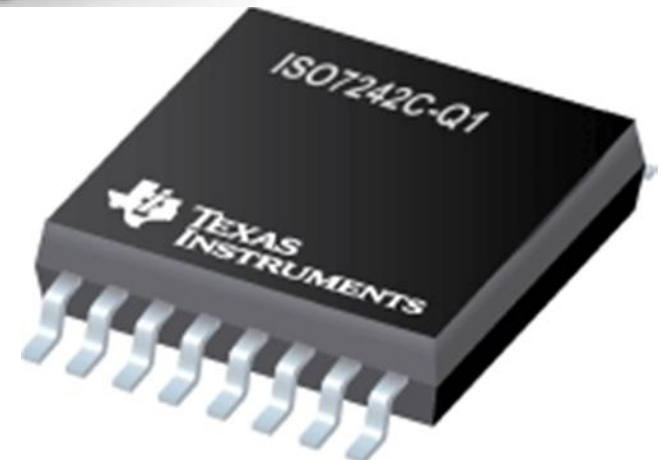
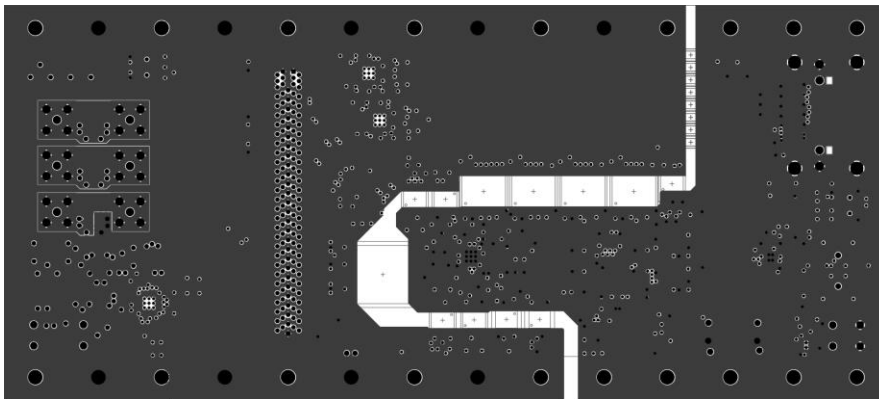
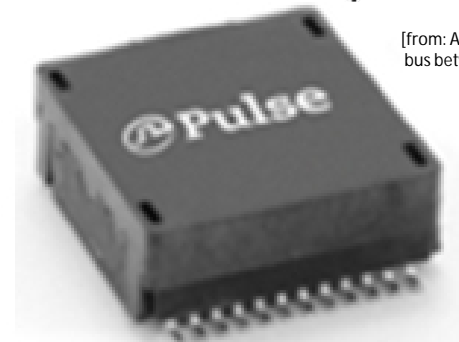


# Galvanic Isolation

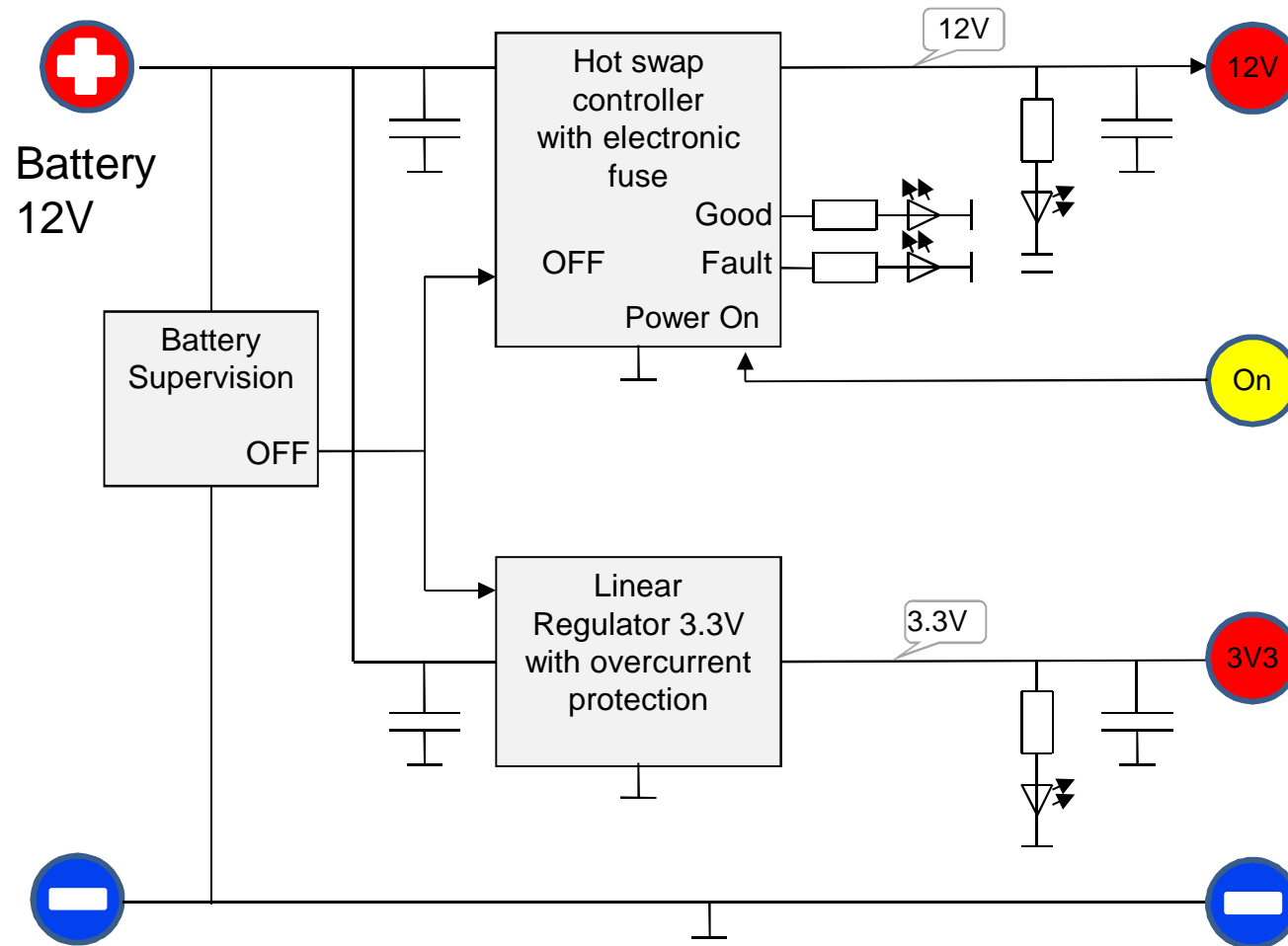
- *Between controller & measurement part of adapter board*
- *Opto coupler for I<sup>2</sup>C and static signals*
- *Capacitors for PCIe*
- *Transformer for LVDS clocks*
- *Digital isolators for Trigger&Interlock*



[from: AN10364 Opto-electrical isolation of the I<sup>2</sup>C-bus (operating the bus between points with different local ground potential), NXP, Nov 2010]

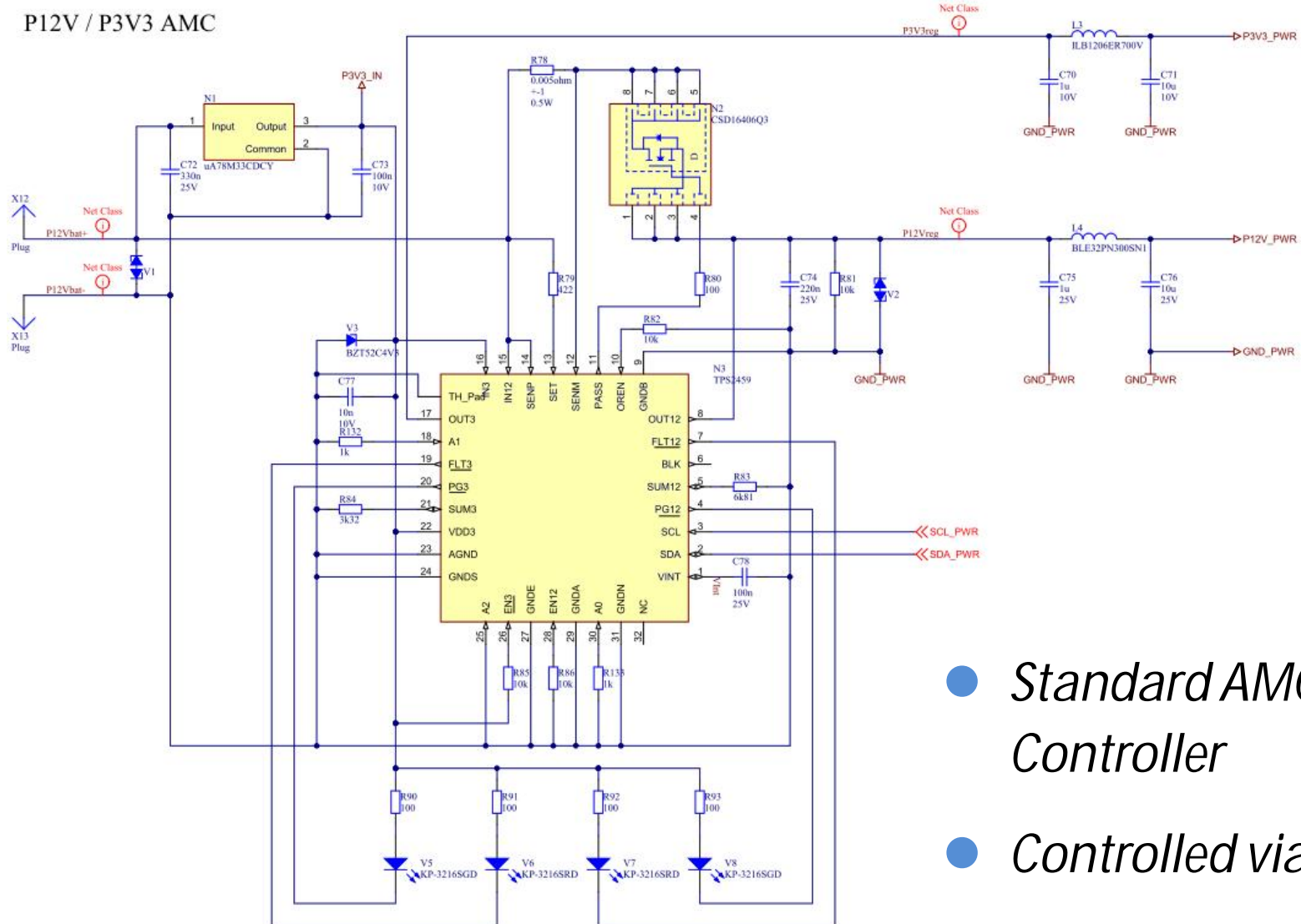


# AMC Power Supply Block Diagram



# Hot Swap Control

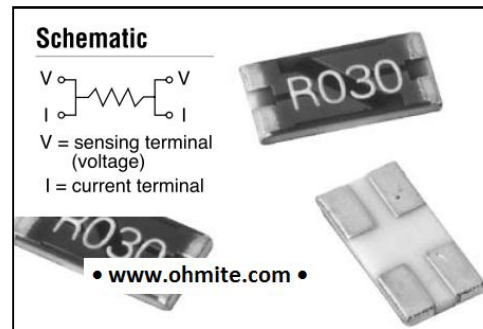
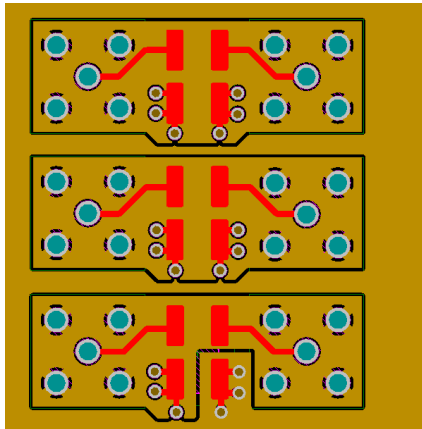
P12V / P3V3 AMC



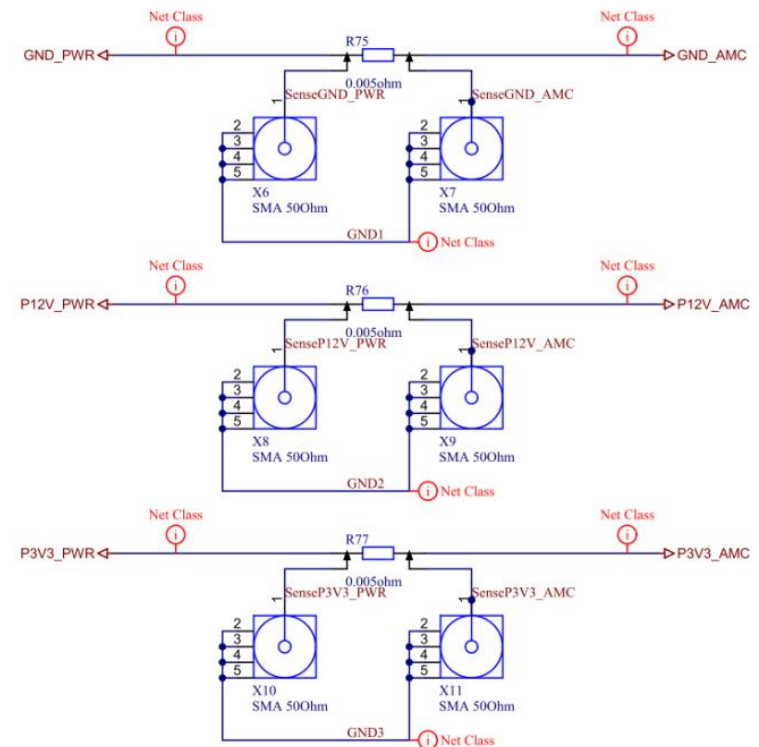
- *Standard AMC Hot Swap Controller*
- *Controlled via I<sup>2</sup>C*
- *Additional 3.3V for Optocoupler*

# Current Measurement

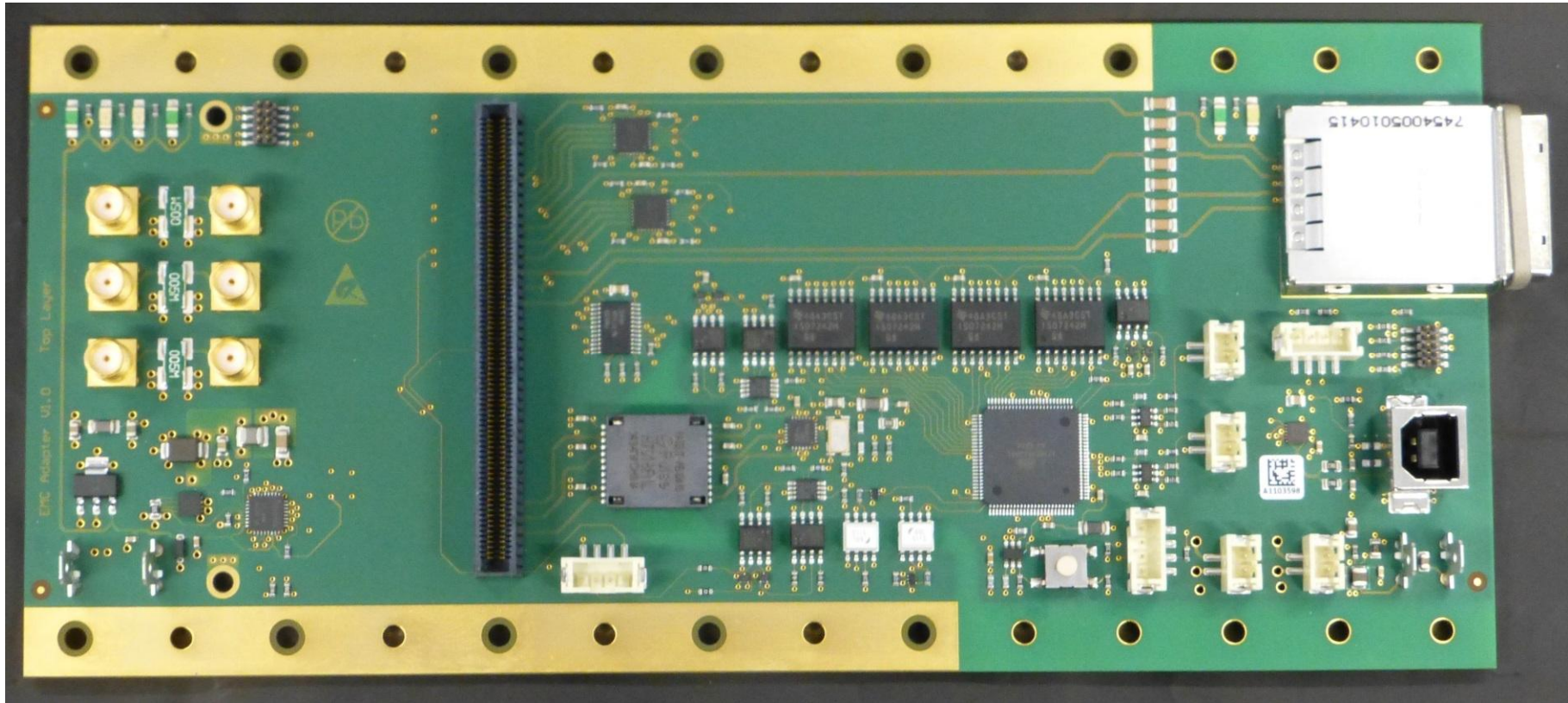
- *Four Terminal High Precision Current Sense*
- *Measurement GND separated*
- *Connection via SMA connectors*



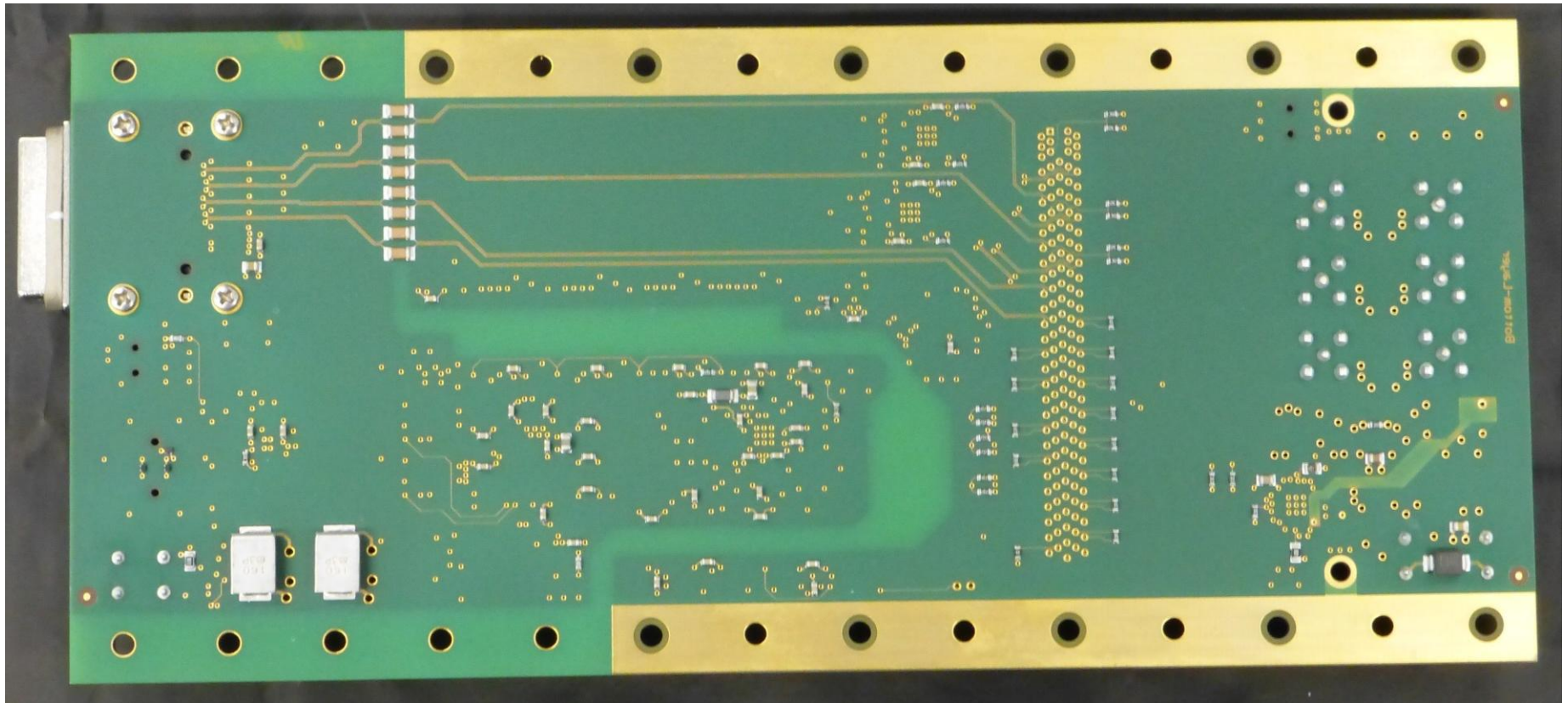
Current Measurement



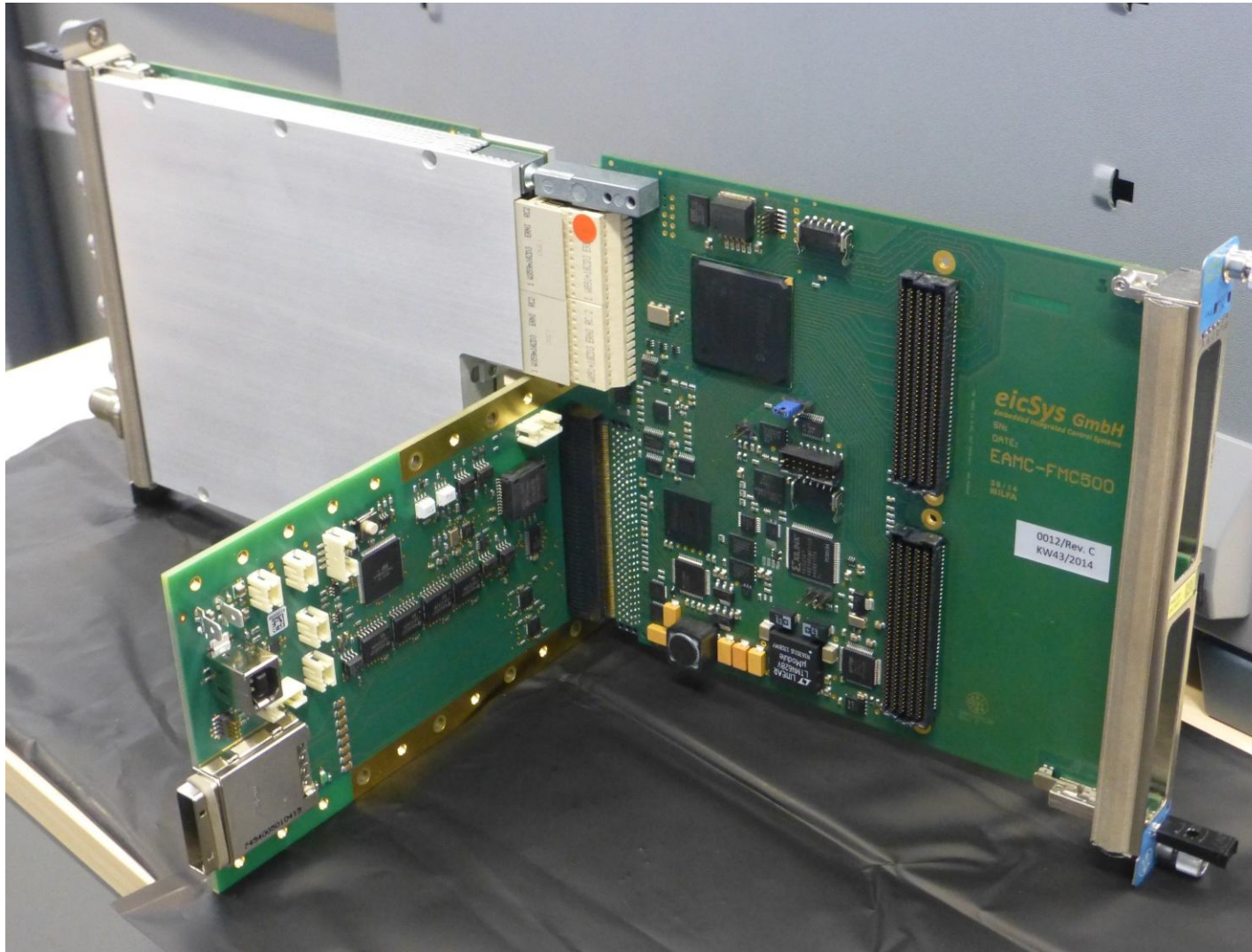
# Board – Component Side



# Board – Solder Side

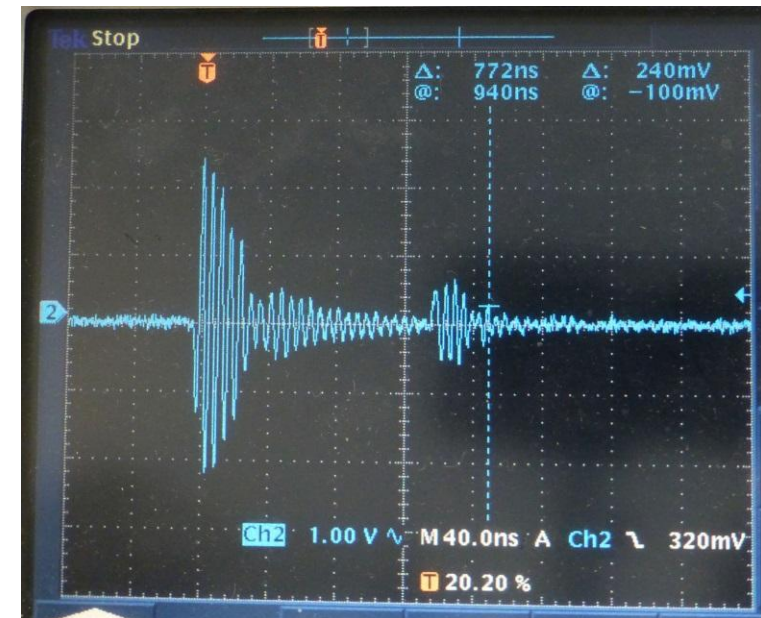


# Setup with AMC/RTM Board



# First experiences Hardware Bring Up

- *Hardware is basically working  
(after some small modifications)  
PCIe / Trigger&Interlock signals not yet tested*
- *Problem:  
3.3 V Controller Power Supply  
extremely susceptible for over/undervoltages  
generates very high noise levels*
- *Workaround: external 3.3 V supply*



# First experiences Firmware Bring Up

- *only basic features tested up to now*
- *Power on of AMC module ok*
- *Programming of Clock generator is working*
- *IPMI not yet tested*
- *Terminal interface via USB only unidirectional*

# Conclusion & Outlook

- *An Adapterboard has been developed to measure noise current that an AMC module introduces to a MTCA.4 system*
- *The measured currents can be used for classifying boards according their contribution to the noise budget of the MTCA.4 system*
- *Using a standalone adapter eliminates system influences*
- *Applying strict galvanic isolation between control electronics and the measurement part reduces noise floor of the measurement setup*
- *Up to now no valid measurements due to low power consumption of tested modules*

Next:

- *Measurement of modules with higher power consumption*
- *Analyzing measured results in order to develop a classification scheme*



# Thank you

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